

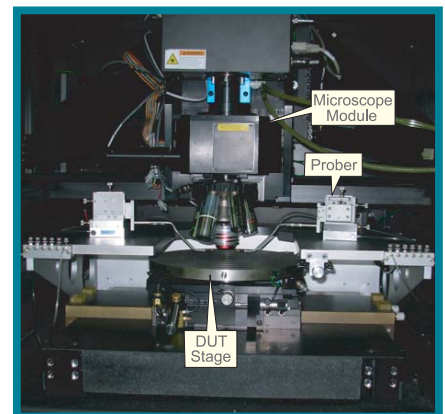
SEMICAPS 1100 CONFIGURATION

UPRIGHT ANALYTICAL SYSTEM



Features

- For backside and frontside analysis of wafers, wafer parts and packaged devices
- Ultra-stable system compatible for probing FIB pads
- Compatible with third-party probe stations, probe cards and manipulators
- High resolution stage with 20nm resolution and 0.5 μ m repeatability
- Centric and Aplanatic Refractive Solid Immersion Lens (RSIL) option
- CAD interface option
- Compatible with thermal management solutions
- Techniques include:
 - Laser Timing Probe (LTP) with frequency mapping for locating signals
 - Scanning Optical Microscopy (SOM) with best-in-class sensitivity for static and dynamic laser induced techniques
 - Photon Emission Microscopy (PEM) with LN2-free, low noise InGaAs or Si-CCD camera
 - Thermal Microscopy (THM) with InSb camera



300mm Probe Station

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